

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π -MOSV)

TENTATIVE

2 S K 3 3 9 9

Switching Regulator Applications

- Low drain-source ON resistance: $R_{DS(ON)} = 0.54 \Omega$ (typ)
 - High forward transfer admittance: $|Y_{fs}| = 5.2 \text{ S}$ (typ)
 - Low leakage current: $ID_{SS} = 100 \mu\text{A}$ (max) ($V_{DSS} = 600 \text{ V}$)
 - Enhancement model: $V_{th} = 3.0\text{--}5.0 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V _{DSS}	600	V
Drain-gate voltage ($R_{GS} = 20\text{ k}\Omega$)		V _{DGR}	600	V
Gate-source voltage		V _{GSS}	±30	V
Drain current	DC	I _D	10	A
	Pulse	I _{DP}	40	
Drain power dissipation ($T_c = 25^\circ\text{C}$)		P _D	100	W
Single pulse avalanche energy (Note2)		E _{AS}	363	mJ
Avalanche current		I _{AR}	10	A
Repetitive avalanche energy (Note1)		E _{AR}	10	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C

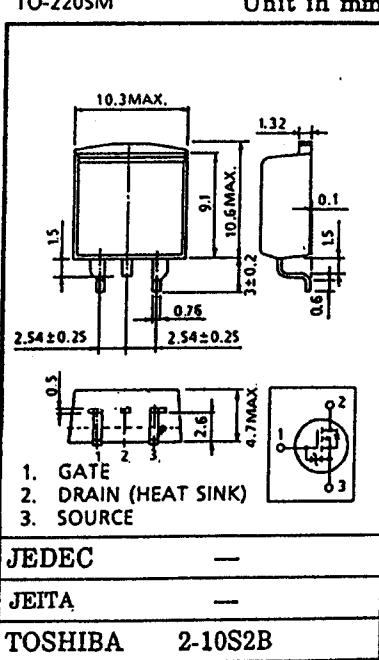
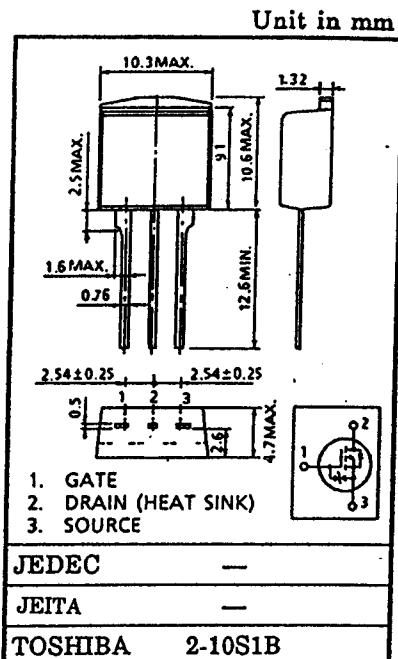
Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th} (ch-c)	1.25	°C/W
Thermal resistance, channel to ambient	R _{th} (ch-a)	83.3	°C/W

Note1: Repetitive rating: pulse width limited by max junction temperature.

Note2: $V_{DD} = 90$ V, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 6.36$ mH,
 $R_G = 25 \Omega$, $I_{AR} = 10$ A

This transistor is an electrostatic sensitive device.
Please handle with caution.



Weight : 1.5 g

Electrical Characteristics ($T_a = 25^\circ C$)

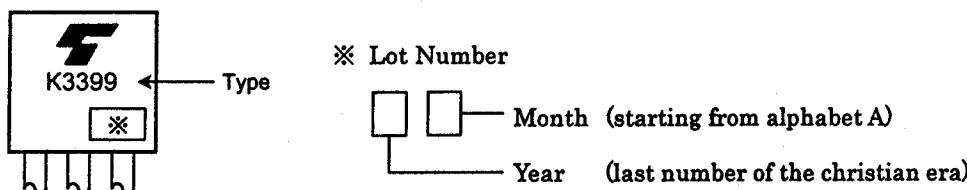
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Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit	
Gate leakage current	I_{GSS}	$V_{GS} = \pm 25 V, V_{DS} = 0 V$	—	—	± 10	μA	
Gate-source breakdown voltage	$V_{(BR) GSS}$	$I_G = \pm 10 \mu A, V_{DS} = 0 V$	± 30	—	—	V	
Drain cut-off current	I_{DSS}	$V_{DS} = 600 V, V_{GS} = 0 V$	—	—	100	μA	
Drain-source breakdown voltage	$V_{(BR) DSS}$	$I_D = 10 mA, V_{GS} = 0 V$	600	—	—	V	
Gate threshold voltage	V_{th}	$V_{DS} = 10 V, I_D = 1 mA$	3.0	—	5.0	V	
Drain-source ON resistance	$R_{DS (ON)}$	$V_{GS} = 10 V, I_D = 5 A$	—	0.54	0.75	Ω	
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = 10 V, I_D = 5 A$	2.0	5.2	—	S	
Input capacitance	C_{iss}	$V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz$	—	1750	—	pF	
Reverse transfer capacitance	C_{rss}		—	11	—		
Output capacitance	C_{oss}		—	170	—		
Switching time	Rise time	t_r	 $V_{IN}: t_r, t_f < 5 \text{ ns}$ $Duty \leq 1\%, t_w = 10 \mu\text{s}$	—	15	—	ns
	Turn-on time	t_{on}		—	40	—	
	Fall time	t_f		—	8	—	
	Turn-off time	t_{off}		—	35	—	
Total gate charge (Gate-source plus gate-drain)	Q_g	$V_{DD} = 400 V, V_{GS} = 10 V, I_D = 10 A$	—	35	—	nC	
Gate-source charge	Q_{gs}		—	15	—		
Gate-drain ("Miller") charge	Q_{gd}		—	20	—		

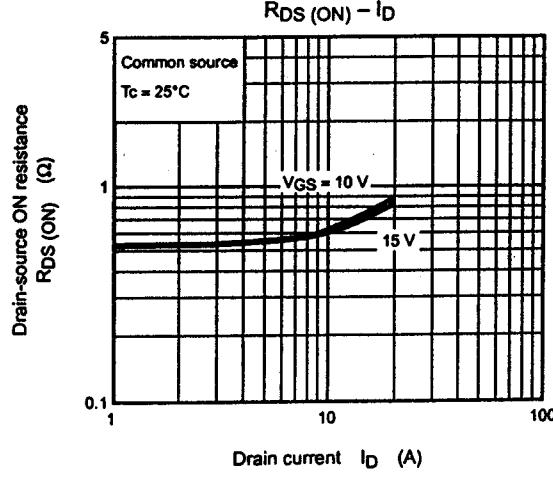
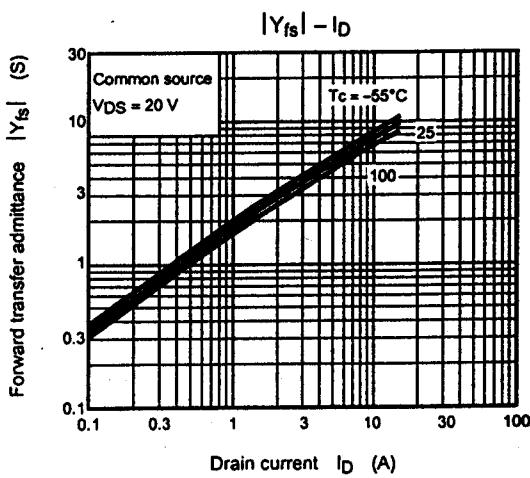
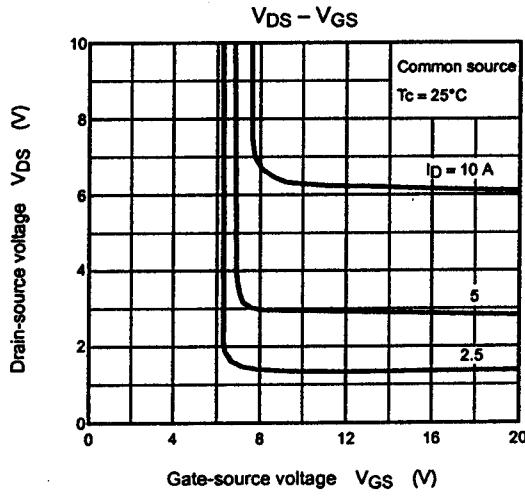
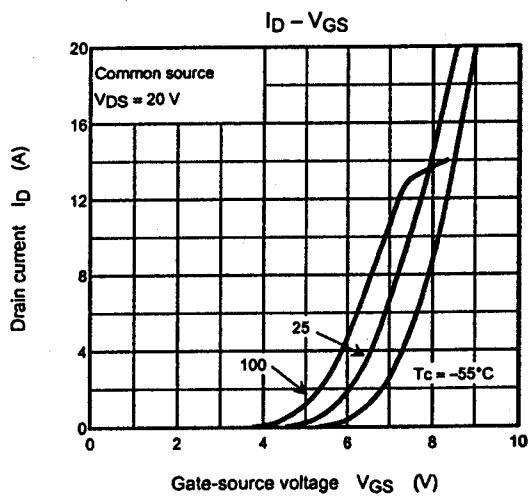
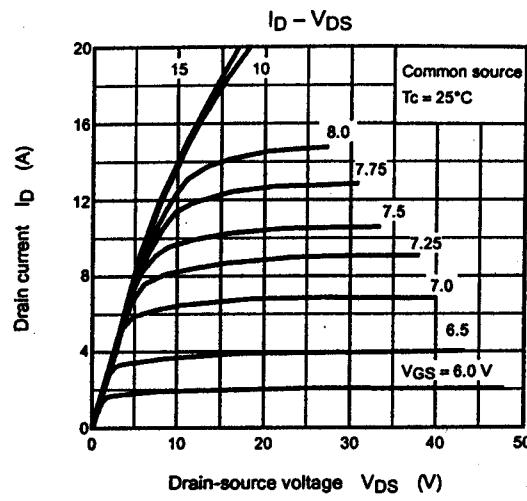
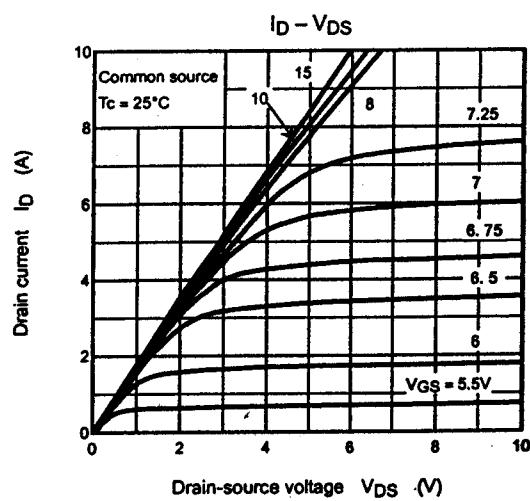
Source-Drain Diode Ratings and Characteristics ($T_a = 25^\circ C$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current	I_{DR}	—	—	—	10	A
Pulse drain reverse current	I_{DRP}	—	—	—	40	A
Diode forward voltage	V_{DSF}	$I_{DR} = 10 A, V_{GS} = 0 V$	—	—	-1.7	V
Reverse recovery time	t_{rr}	$I_{DR} = 10 A, V_{GS} = 0 V$	—	1300	—	ns
Reverse recovery charge	Q_{rr}	$dI_{DR}/dt = 100 A/\mu s$	—	16	—	μC

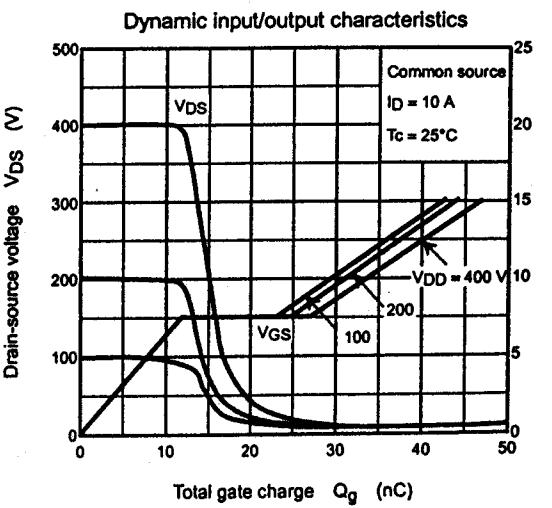
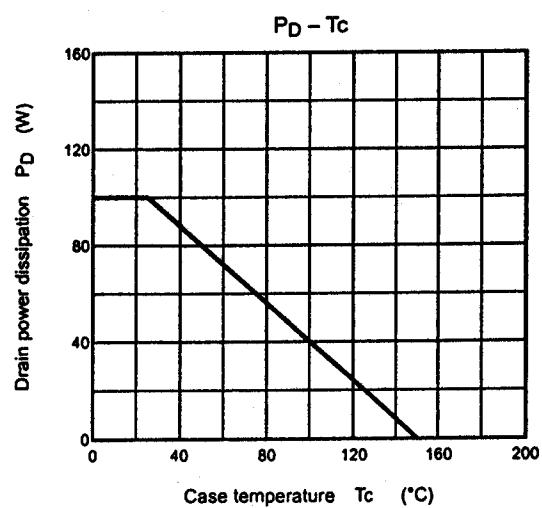
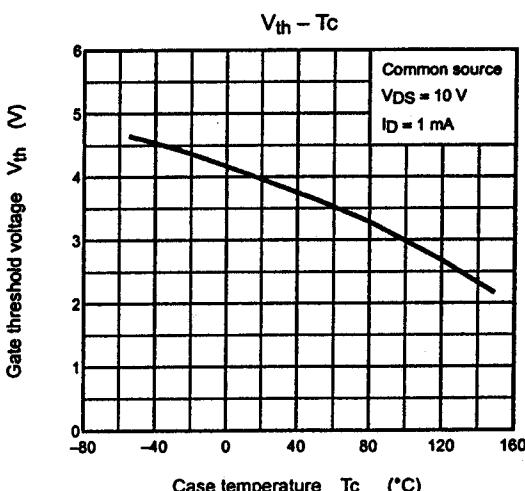
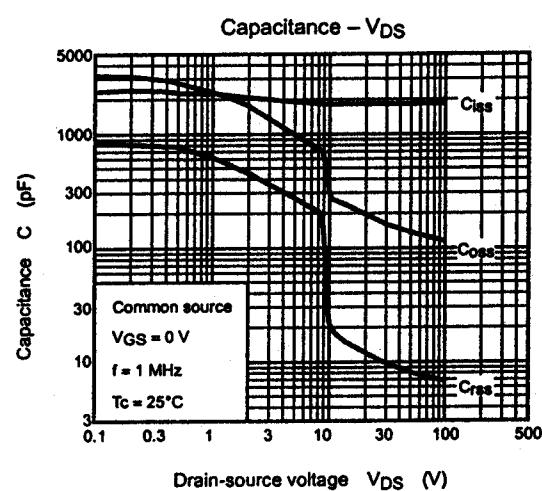
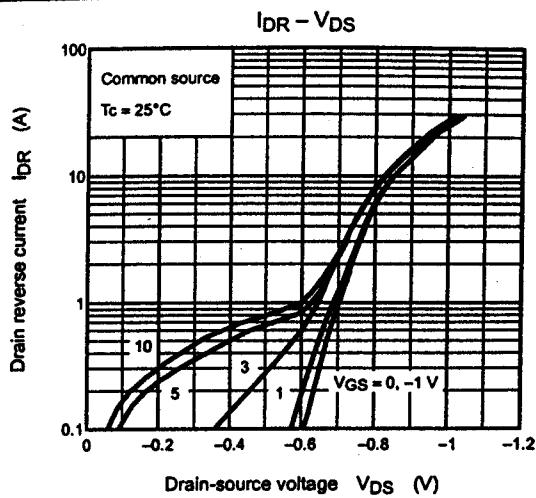
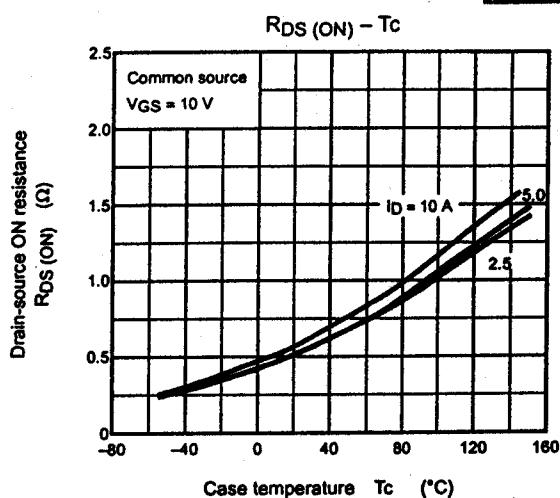
Marking



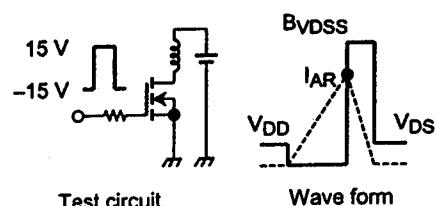
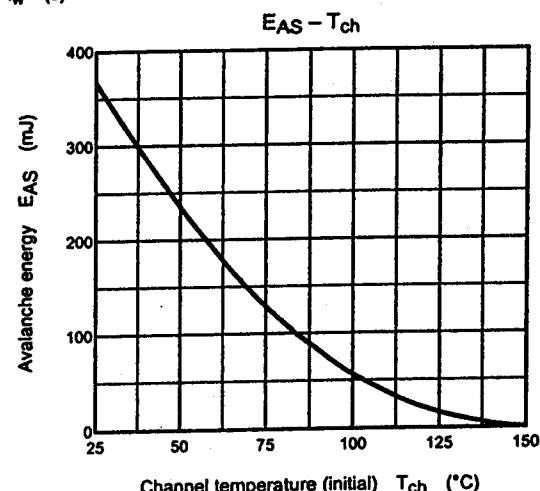
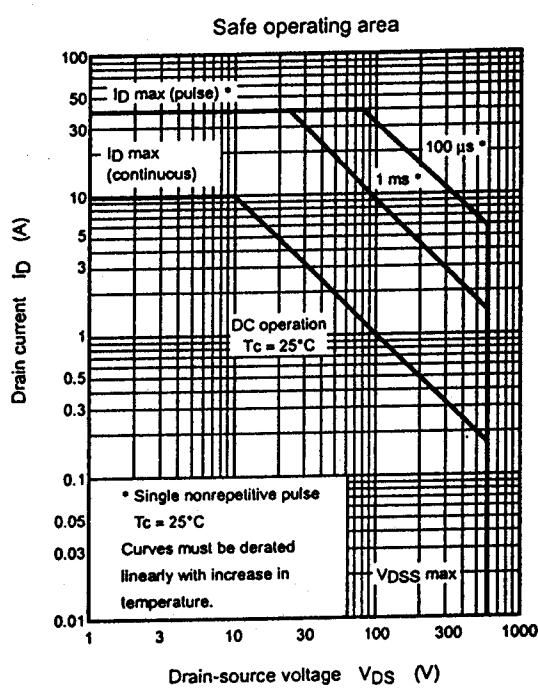
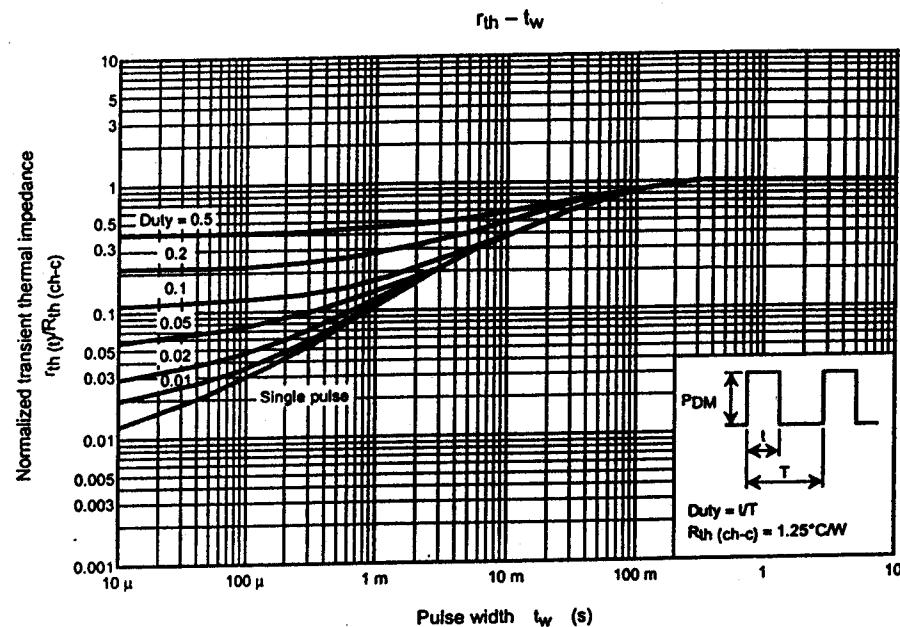
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$$EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$

SAFETY RESTRICTIONS ON PRODUCT USE

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